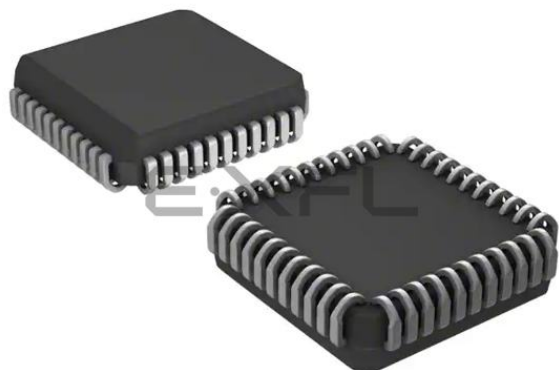




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	34
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	44-LCC (J-Lead)
Supplier Device Package	44-PLCC (16.59x16.59)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-2pl44i

2 40MX and 42MX FPGA Families

2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

2.2 Product Profile

The following table gives the features of the products.

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
Logic Modules						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
Clock-to-Out	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)						
	–	–	–	–	–	10
Dedicated Flip-Flops	–	–	348	624	954	1,230

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Microsemi's integrated verification and logic analysis tool. Another tool included in the Libero software is the SmartGen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design.

Microsemi's Libero software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synopsys, and Cadence design systems.

See the Libero IDE web content at www.microsemi.com/soc/products/software/libero/default.aspx for further information on licensing and current operating system support.

3.6 Related Documents

The following sections give the list of related documents which can be referred for this datasheet.

3.6.1 Application Notes

- *AC278: BSDL Files Format Description*
- *AC225: Programming Antifuse Devices*
- *AC168: Implementation of Security in Microsemi Antifuse FPGAs*

3.6.2 User Guides and Manuals

- *Antifuse Macro Library Guide*
- *Silicon Sculptor Programmers User Guide*

3.6.3 Miscellaneous

Libero IDE Flow Diagram

3.7 5.0 V Operating Conditions

The following tables show 5.0 V operating conditions.

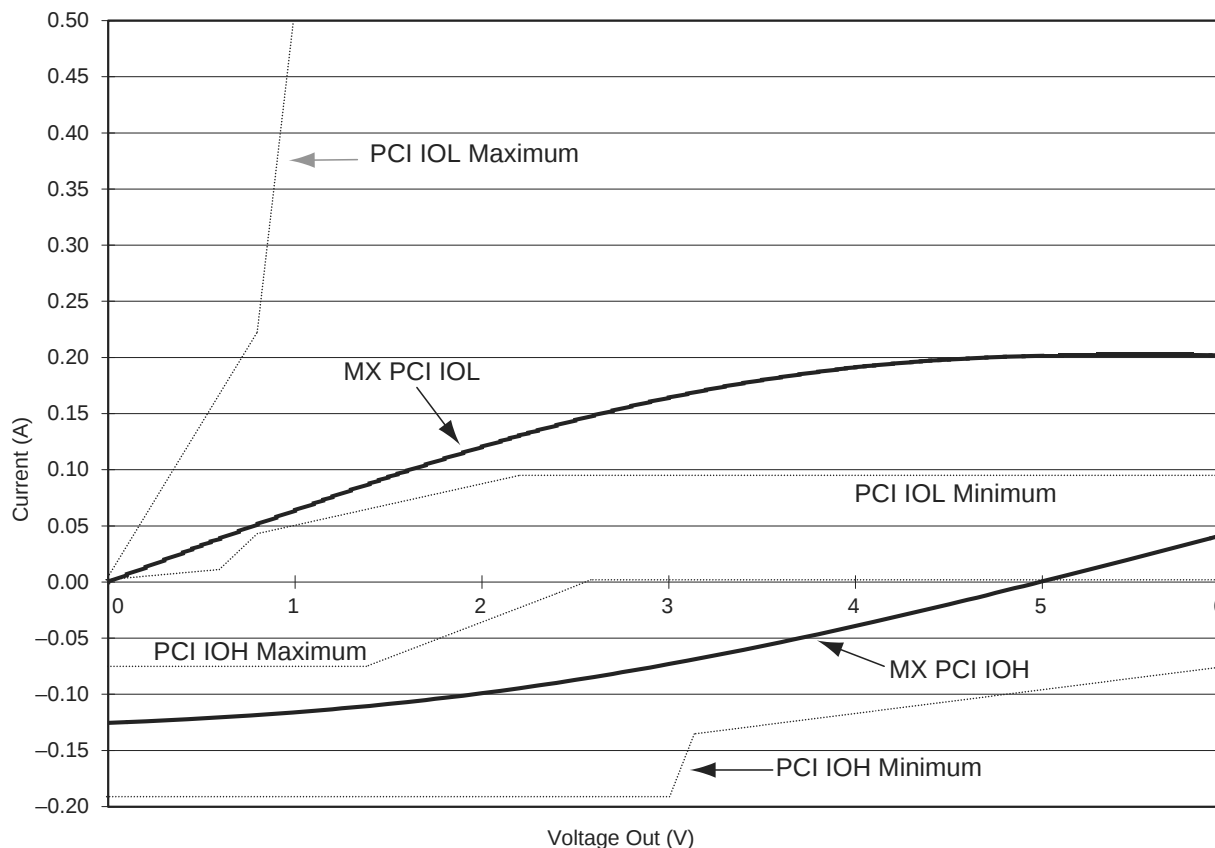
Table 12 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCC+0.5	V
VO	Output Voltage	–0.5 to VCC+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 13 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCI+0.5	V
VO	Output Voltage	–0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Figure 16 • Typical Output Drive Characteristics (Based Upon Measured Data)

3.9.4 Junction Temperature (T_J)

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because the heat generated from dynamic power consumption is usually hotter than the ambient temperature. The following equation can be used to calculate junction temperature.

$$\text{Junction Temperature} = \Delta T + T_a(1)$$

EQ 4

where:

- T_a = Ambient Temperature
- ΔT = Temperature gradient between junction (silicon) and ambient
- $\Delta T = \theta_{ja} * P$ (2)
- P = Power
- θ_{ja} = Junction to ambient of package. θ_{ja} numbers are located in Table 27, page 29.

3.9.5 Package Thermal Characteristics

The device junction-to-case thermal characteristic is θ_{jc} , and the junction-to-ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

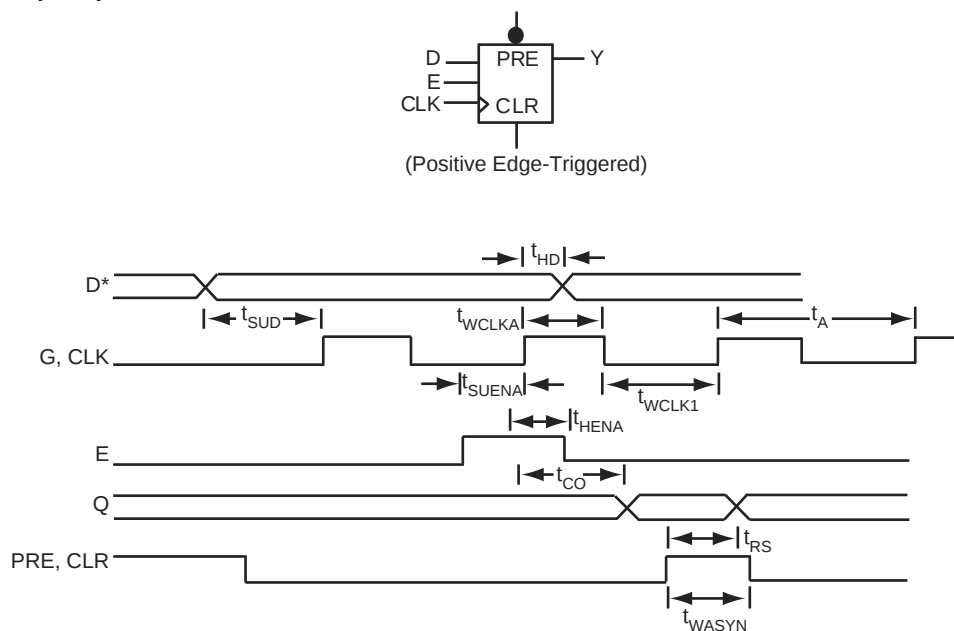
The maximum junction temperature is 150°C.

Maximum power dissipation for commercial- and industrial-grade devices is a function of θ_{ja} .

3.10.2 Sequential Module Timing Characteristics

The following figure shows sequential module timing characteristics.

Figure 25 • Flip-Flops and Latches



Note: *D represents all data functions involving A, B, and S for multiplexed flip-flops.

3.10.3 Sequential Timing Characteristics

The following figures show sequential timing characteristics.

Figure 26 • Input Buffer Latches

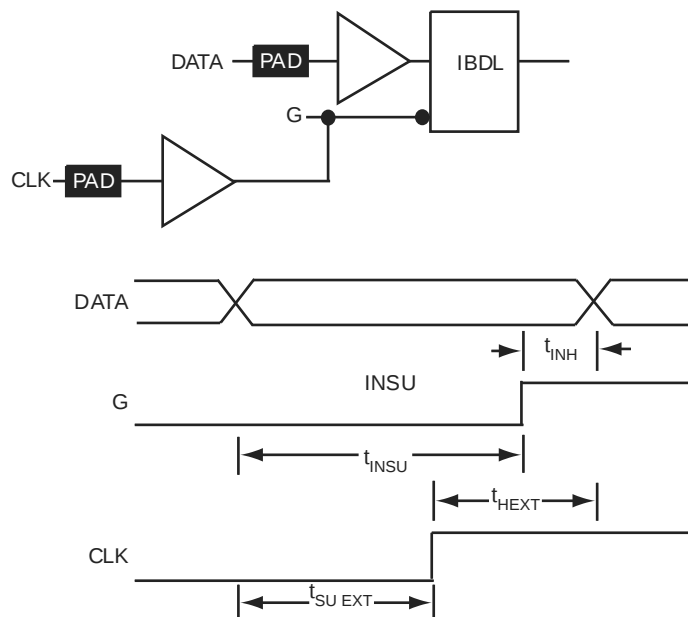


Table 33 • Timing Parameters for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
$t_{SU(PTP)}$	Input Set-Up Time to CLK—Point-to-Point	10, 12 ²	—	1.5	—	1.5	—	ns
t_H	Input Hold to CLK	0	—	0	—	0	—	ns

1. TOFF is system dependent. MX PCI devices have 7.4 ns turn-off time, reflection is typically an additional 10 ns.
2. REQ# and GNT# are point-to-point signals and have different output valid delay and input setup times than do bussed signals. GNT# has a setup of 10; REW# has a setup of 12.

3.11.6.1 Timing Characteristics

The following tables list the timing characteristics.

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t _{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t _{PD2}	Dual-Module Macros		2.7		3.1		3.5		4.1		5.7	ns
t _{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays ¹												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.8	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.1		2.4		2.8		3.9	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.7		3.0		3.6		5.0	ns
t _{RD4}	FO = 4 Routing Delay		2.9		3.3		3.7		4.4		6.1	ns
t _{RD8}	FO = 8 Routing Delay		4.9		5.7		6.5		7.6		10.6	ns
Logic Module Sequential Timing ²												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t _A	Flip-Flop Clock Input Period	4.8		5.6		6.3		7.5		10.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181		168		154		134		80	MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD4}	FO = 4 Routing Delay	1.9		2.1		2.4		2.9		4.0		ns
t _{RD8}	FO = 8 Routing Delay	3.2		3.6		4.1		4.8		6.7		ns
Logic Module Sequential Timing ^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.7		5.3		6.0		7.0		9.8		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.2		6.9		7.8		9.2		12.9		ns
t _A	Flip-Flop Clock Input Period	5.0		5.6		6.2		7.1		9.9		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.3		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency	161		146		135		117		70		MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t _{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units	
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Logic Module Propagation Delays ¹													
t _{PD1}	Single Module		1.4		1.5		1.7		2.0		2.8		ns
t _{CO}	Sequential Clock-to-Q		1.4		1.6		1.8		2.1		3.0		ns
t _{GO}	Latch G-to-Q		1.4		1.5		1.7		2.0		2.8		ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.6		1.7		2.0		2.3		3.3		ns
Logic Module Predicted Routing Delays ²													
t _{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.6		ns
t _{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1		ns

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD3}	FO = 3 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t _{RD4}	FO = 4 Routing Delay		1.6		1.7		2.0		2.3		3.2	ns
t _{RD8}	FO = 8 Routing Delay		2.6		2.9		3.2		3.8		5.3	ns
Logic Module Sequential Timing^{3,4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.3		0.4		0.4		0.5		0.7	ns
t _{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up		0.7		0.8		0.9		1.0		1.4	ns
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.4		3.8		4.3		5.0		7.1	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		4.5		5.0		5.6		6.6		9.2	ns
t _A	Flip-Flop Clock Input Period		6.8		7.6		8.6		10.1		14.1	ns
t _{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{INSU}	Input Buffer Latch Set-Up		0.5		0.5		0.6		0.7		1.0	ns
t _{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{OUTSU}	Output Buffer Latch Set-Up		0.5		0.5		0.6		0.7		1.0	ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		215		195		179		156		94	MHz
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH		1.1		1.2		1.3		1.6		2.2	ns
t _{INYL}	Pad-to-Y LOW		0.8		0.9		1.0		1.2		1.7	ns
t _{INGH}	G to Y HIGH		1.4		1.6		1.8		2.1		2.9	ns
t _{INGL}	G to Y LOW		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays²												
t _{IRD1}	FO = 1 Routing Delay		1.8		2.0		2.3		2.7		4.0	ns
t _{IRD2}	FO = 2 Routing Delay		2.1		2.3		2.6		3.1		4.3	ns
t _{IRD3}	FO = 3 Routing Delay		2.3		2.6		3.0		3.5		4.9	ns
t _{IRD4}	FO = 4 Routing Delay		2.6		3.0		3.3		3.9		5.4	ns
t _{IRD8}	FO = 8 Routing Delay		3.6		4.0		4.6		5.4		7.5	ns
Global Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32	2.6		2.9		3.3		3.9		5.4	ns
		FO = 384	2.9		3.2		3.6		4.3		6.0	ns
t _{CKL}	Input HIGH to LOW	FO = 32	3.8		4.2		4.8		5.6		7.8	ns
		FO = 384	4.5		5.0		5.6		6.6		9.2	ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	3.2		3.5		4.0		4.7		6.6	ns
		FO = 384	3.7		4.1		4.6		5.4		7.6	ns

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t _{DHL}	Data-to-Pad LOW		2.8		3.2		3.6		4.2		5.9	ns
t _{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t _{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.9	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t _{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t _{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.6		6.1		6.9		8.1		11.4	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.3		1.5		1.7		2.0		2.7	ns
t _{PDD}	Internal Decode Module Delay		1.6		1.8		2.0		2.4		3.3	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.2		1.4		2.0	ns
t _{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t _{RD3}	FO =3 Routing Delay		1.6		1.8		2.0		2.4		3.4	ns
t _{RD4}	FO = 4 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns
t _{RD5}	FO = 8 Routing Delay		3.3		3.7		4.2		4.9		6.9	ns
t _{RDD}	Decode-to-Output Routing Delay		0.3		0.4		0.4		0.5		0.7	ns
Logic Module Sequential Timing ^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.3		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		1.6		1.7		2.0		2.3		3.2	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.5		6.4		9.0		ns
Synchronous SRAM Operations												
t _{RC}	Read Cycle Time		6.8		7.5		8.5		10.0		14.0	ns
t _{WC}	Write Cycle Time		6.8		7.5		8.5		10.0		14.0	ns
t _{RCKHL}	Clock HIGH/LOW Time		3.4		3.8		4.3		5.0		7.0	ns
t _{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t _{ADSU}	Address/Data Set-Up Time		1.6		1.8		2.0		2.4		3.4	ns
Synchronous SRAM Operations (continued)												
t _{ADH}	Address/Data Hold Time		0.0		0.0		0.0		0.0		0.0	ns
t _{RENSU}	Read Enable Set-Up		0.6		0.7		0.8		0.9		1.3	ns
t _{RENH}	Read Enable Hold		3.4		3.8		4.3		5.0		7.0	ns
t _{WENSU}	Write Enable Set-Up		2.7		3.0		3.4		4.0		5.6	ns
t _{WENH}	Write Enable Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{BENS}	Block Enable Set-Up		2.8		3.1		3.5		4.1		5.7	ns
t _{BENH}	Block Enable Hold		0.0		0.0		0.0		0.0		0.0	ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.8		3.2		3.6		4.2		5.9		ns
		FO = 635	3.3		3.7		4.2		4.9		6.9		ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	5.5		6.1		6.6		7.6		12.7		ns
		FO = 635	6.0		6.6		7.2		8.3		13.8		ns
f _{MAX}	Maximum Datapath Frequency	FO = 32		180		164		151		131		79	MHz
		FO = 635		166		151		139		121		73	MHz
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH			2.6		2.8		3.2		3.8		5.3	ns
t _{DHL}	Data-to-Pad LOW			3.0		3.3		3.7		4.4		6.2	ns
t _{ENZH}	Enable Pad Z to HIGH			2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW			3.0		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z			5.3		5.8		6.6		7.8		10.9	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD5}	FO = 8 Routing Delay		4.6		5.2		5.8		6.9		9.6	ns
t _{RDD}	Decode-to-Output Routing Delay		0.5		0.5		0.6		0.7		1.0	ns
Logic Module Sequential Timing^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{GO}	Latch Gate-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		2.2		2.4		2.7		3.2		4.5	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	1.0		1.1		1.2		1.4		2.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.6		5.2		5.8		6.9		9.6	ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.1		6.8		7.7		9.0		12.6	ns
Synchronous SRAM Operations												
t _{RC}	Read Cycle Time		9.5		10.5		11.9		14.0		19.6	ns
t _{WC}	Write Cycle Time		9.5		10.5		11.9		14.0		19.6	ns
t _{RCKHL}	Clock HIGH/LOW Time		4.8		5.3		6.0		7.0		9.8	ns
t _{RCO}	Data Valid After Clock HIGH/LOW		4.8		5.3		6.0		7.0		9.8	ns
t _{ADSU}	Address/Data Set-Up Time		2.3		2.5		2.8		3.4		4.8	ns

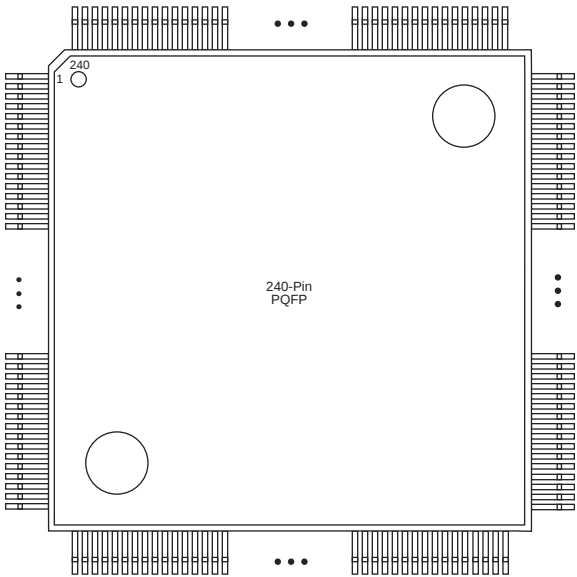
Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
58	VCCI	VCCI	VCCI
59	GND	GND	GND
60	VCCA	VCCA	VCCA
61	LP	LP	LP
62	I/O	I/O	TCK, I/O
63	I/O	I/O	I/O
64	GND	GND	GND
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	I/O	I/O	I/O
69	GND	GND	GND
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	NC	I/O	I/O
76	I/O	I/O	I/O
77	NC	I/O	I/O
78	I/O	I/O	I/O
79	NC	I/O	I/O
80	GND	GND	GND
81	I/O	I/O	I/O
82	SDO, I/O	SDO, I/O	SDO, TDO, I/O
83	I/O	I/O	WD, I/O
84	I/O	I/O	WD, I/O
85	I/O	I/O	I/O
86	NC	VCCI	VCCI
87	I/O	I/O	I/O
88	I/O	I/O	WD, I/O
89	GND	GND	GND
90	NC	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
206	I/O	I/O	I/O
207	DCLK, I/O	DCLK, I/O	DCLK, I/O
208	I/O	I/O	I/O

Figure 45 • PQ240



Note: This figure shows the 240-Pin PQFP Package top view.

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
1	I/O
2	DCLK, I/O
3	I/O
4	I/O
5	I/O
6	WD, I/O
7	WD, I/O
8	VCCI
9	I/O
10	I/O
11	I/O
12	I/O
13	I/O
14	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
49	I/O	I/O
50	CLK, I/O	CLK, I/O
51	I/O	I/O
52	MODE	MODE
53	VCC	VCC
54	NC	I/O
55	NC	I/O
56	NC	I/O
57	SDI, I/O	SDI, I/O
58	DCLK, I/O	DCLK, I/O
59	PRA, I/O	PRA, I/O
60	NC	NC
61	PRB, I/O	PRB, I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	I/O	I/O
68	GND	GND
69	I/O	I/O
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	VCC	VCC
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

Figure 49 • CQ208

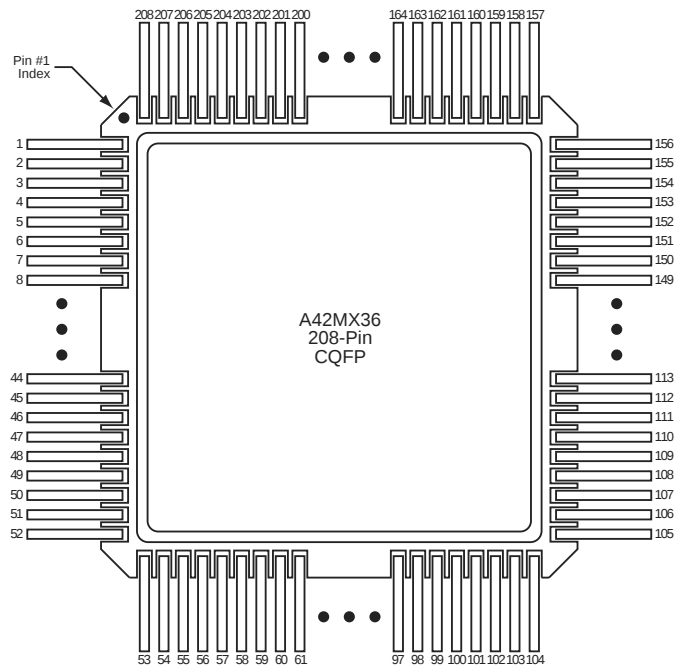


Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
185	I/O
186	CLKB, I/O
187	I/O
188	PRB, I/O
189	I/O
190	WD, I/O
191	WD, I/O
192	I/O
193	I/O
194	WD, I/O
195	WD, I/O
196	QCLKC, I/O
197	I/O
198	I/O
199	I/O
200	I/O
201	I/O
202	VCCI
203	WD, I/O
204	WD, I/O
205	I/O
206	I/O
207	DCLK, I/O
208	I/O

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
B3	I/O
A2	I/O
C3	DCLK
B5	GND A
E12	GND A
J2	GND A
M9	GND A
B9	GND I
C5	GND I
E11	GND I
F4	GND I
J3	GND I
J11	GND I
L5	GND I
L9	GND I
C9	GND Q
E3	GND Q
K12	GND Q
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI

Table 62 • CQ172

138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK